

Features

- ★ Advanced Trench MOS Technology
- ★ 100% EAS Guaranteed
- ★ Reliable and Rugged
- ★ Green Device Available

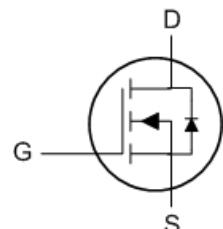
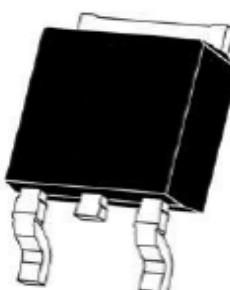
Product Summary

| BVDSS | RDS(ON) | ID |
|-------|---------|-----|
| 100V | 26mΩ | 30A |

Applications

- ★ Synchronous Rectification in SMPS.
- ★ Hard Switching and High Speed Circuit.
- ★ DC/DC in Telecoms and Industrial.

TO252 Pin Configuration



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|---------------------------------------|--|------------|-------|
| V _{DS} | Drain-Source Voltage | 100 | V |
| V _{GS} | Gate-Source Voltage | ±20 | V |
| I _D @T _c =25°C | Continuous Drain Current ¹ | 30 | A |
| I _D @T _c =100°C | Continuous Drain Current ¹ | 18.5 | A |
| I _{DM} | Pulsed Drain Current ² | 120 | A |
| EAS | Single Pulse Avalanche Energy ³ | 64.8 | mJ |
| I _{AS} | Avalanche Current | 36 | A |
| P _D @T _c =25°C | Total Power Dissipation ⁴ | 52 | W |
| T _{STG} | Storage Temperature Range | -55 to 150 | °C |
| T _J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|------------------|--|------|------|------|
| R _{θJA} | Thermal Resistance Junction-ambient ¹ | --- | 50 | °C/W |
| R _{θJC} | Thermal Resistance Junction-case ¹ | --- | 2.4 | °C/W |

N-Ch 100V Fast Switching MOSFETs

Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|--------------------------|--|--|------|------|-----------|------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$ | 100 | --- | --- | V |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance ² | $V_{\text{GS}}=10\text{V}$, $I_D=8\text{A}$ | --- | 22 | 26 | $\text{m}\Omega$ |
| | | $V_{\text{GS}}=4.5\text{V}$, $I_D=4\text{A}$ | --- | 24 | 32 | $\text{m}\Omega$ |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$ | 1.2 | 1.8 | 2.5 | V |
| I_{DSS} | Drain-Source Leakage Current | $V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$ | --- | --- | 1 | uA |
| | | $V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^\circ\text{C}$ | --- | --- | 5 | |
| I_{GSS} | Gate-Source Leakage Current | $V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$ | --- | --- | ± 100 | nA |
| Q_g | Total Gate Charge (10V) | $V_{\text{DS}}=30\text{V}$, $V_{\text{GS}}=10\text{V}$, $I_D=8\text{A}$ | --- | 57 | --- | nC |
| Q_{gs} | Gate-Source Charge | | --- | 8.7 | --- | |
| Q_{gd} | Gate-Drain Charge | | --- | 14 | --- | |
| $T_{\text{d(on)}}$ | Turn-On Delay Time | $V_{\text{DD}}=30\text{V}$, $V_{\text{GS}}=10\text{V}$, $R_G=3.3\Omega$, $I_D=1\text{A}$ | --- | 16.2 | --- | ns |
| T_r | Rise Time | | --- | 41.2 | --- | |
| $T_{\text{d(off)}}$ | Turn-Off Delay Time | | --- | 56.4 | --- | |
| T_f | Fall Time | | --- | 16.2 | --- | |
| C_{iss} | Input Capacitance | $V_{\text{DS}}=25\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$ | --- | 3307 | --- | pF |
| C_{oss} | Output Capacitance | | --- | 201 | --- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 151 | --- | |

Diode Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-----------------|--|---|------|------|------|------|
| I_s | Continuous Source Current ^{1,5} | $V_G=V_D=0\text{V}$, Force Current | --- | --- | 15 | A |
| V_{SD} | Diode Forward Voltage ² | $V_{\text{GS}}=0\text{V}$, $I_s=1\text{A}$, $T_J=25^\circ\text{C}$ | --- | --- | 1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_F=8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$ | --- | 44 | --- | nS |
| Q_{rr} | Reverse Recovery Charge | | --- | 25 | --- | nC |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.1\text{mH}$, $I_{\text{AS}}=36\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

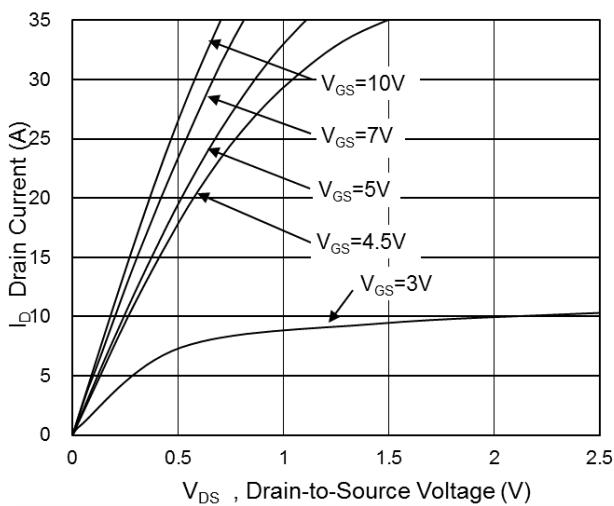


Fig.1 Typical Output Characteristics

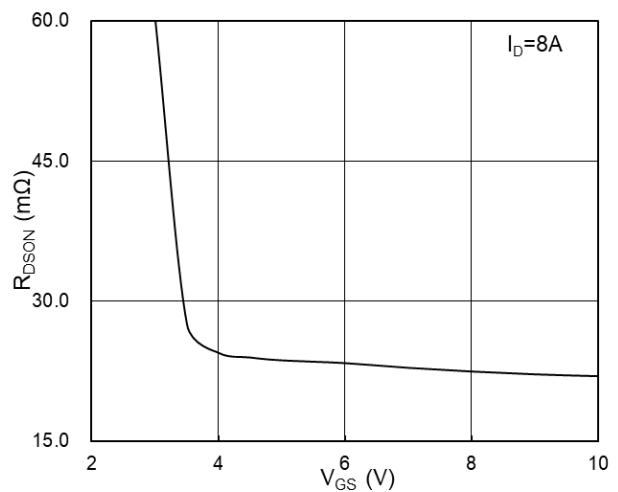


Fig.2 On-Resistance vs G-S Voltage

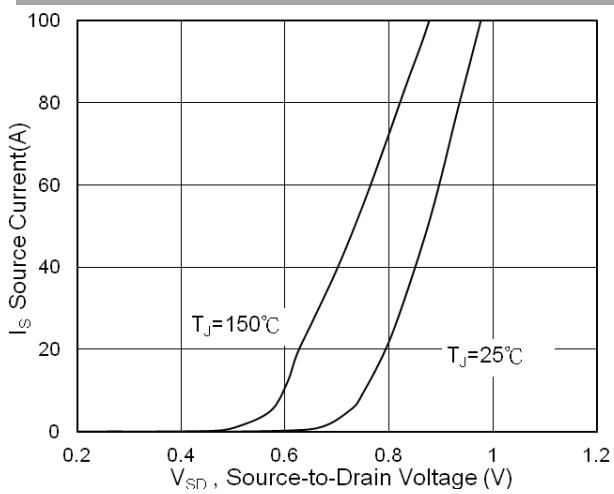


Fig.3 Source-Drain Diode Forward Voltage

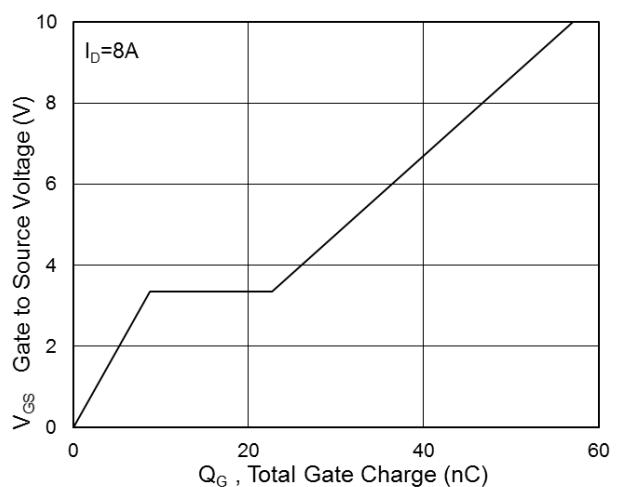


Fig.4 Gate-Charge Characteristics

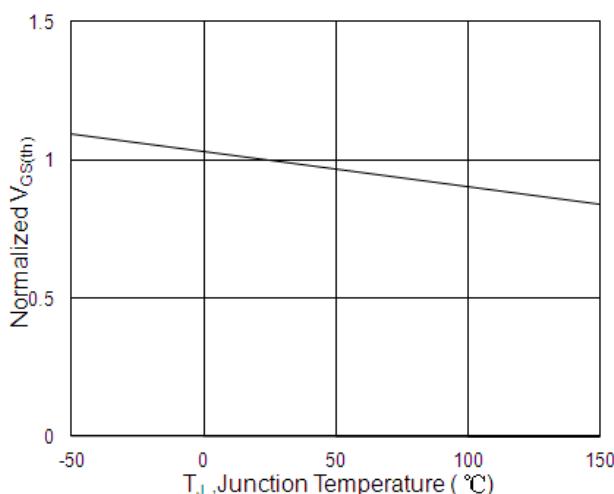


Fig.5 Normalized $V_{GS(th)}$ vs T_J

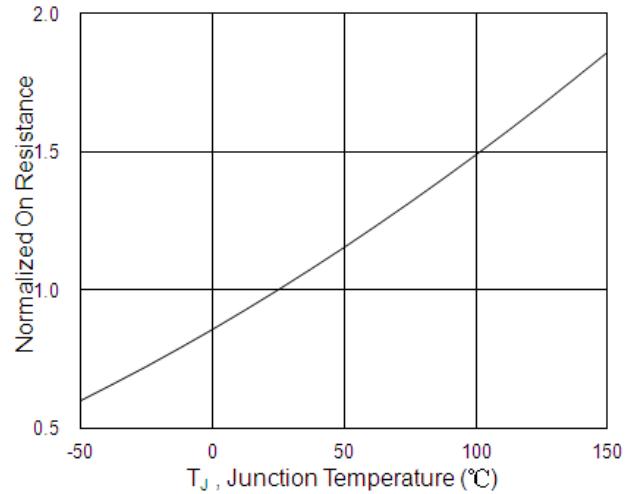


Fig.6 Normalized $R_{DS(on)}$ vs T_J

N-Ch 100V Fast Switching MOSFETs

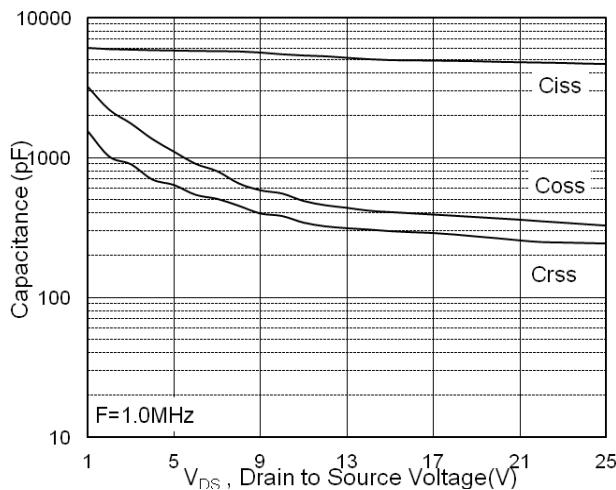


Fig.7 Capacitance

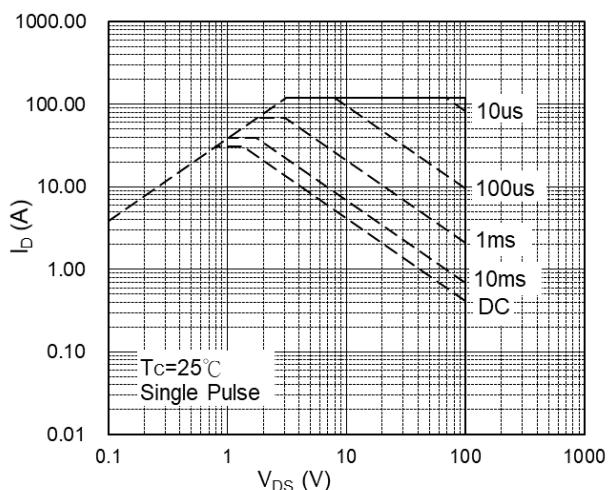


Fig.8 Safe Operating Area

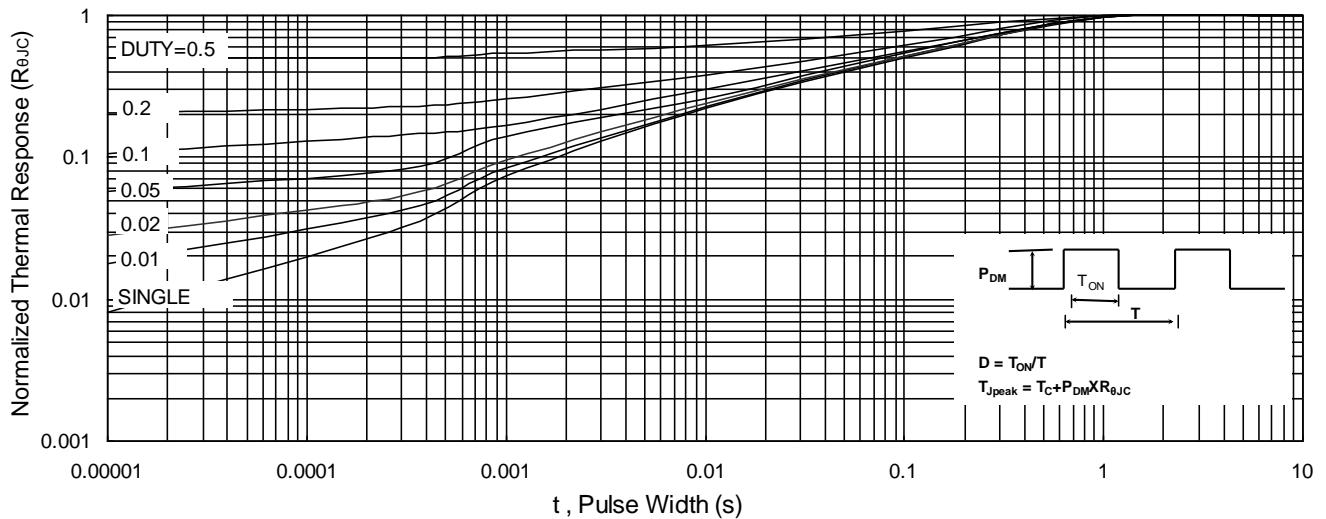


Fig.9 Normalized Maximum Transient Thermal Impedance

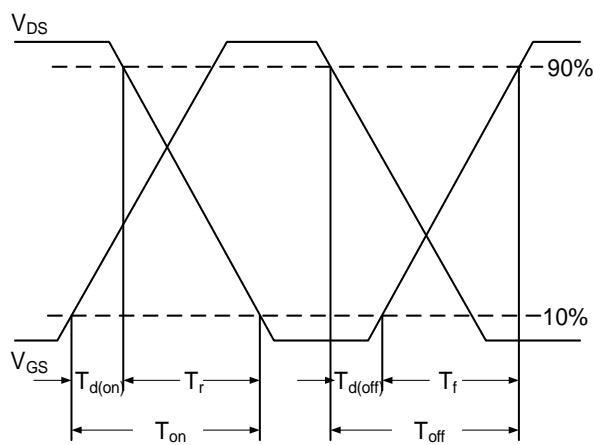


Fig.10 Switching Time Waveform

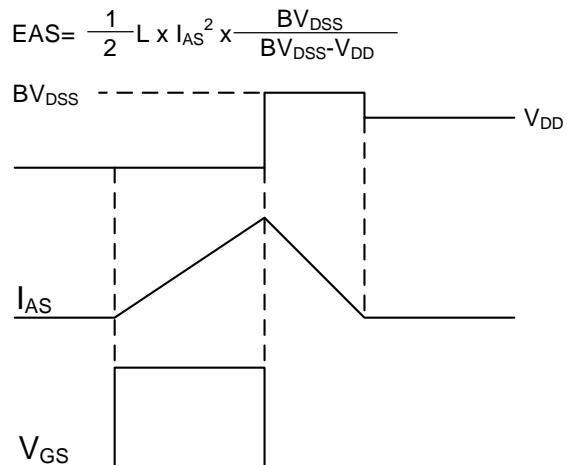


Fig.11 Unclamped Inductive Switching Waveform